# MT40022

# **N-Channel Power MOSFET**

40V,220A,2.5m $\Omega$ 

#### **Features**

- Trench Power MV MOSFET technology
- Low RDS(ON)
- Low Gate Charge
- Opitimized Ruggedness
- RoHS and Halogen-Free Compliant

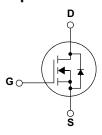
# **Applications**

- DC Motor Driver
- Synchronous Rectification in DC/DC and AC/DC Converters

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## **Simplified Schematic**



MARKING DIAGRAM & PIN ASSIGNMENT



# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

TO-220

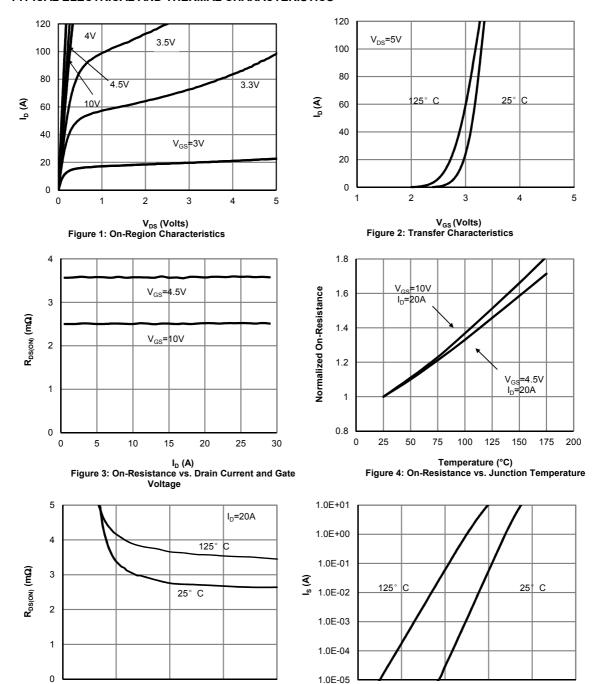
Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		$V_{DS}$	40	V	
Gate-Source Voltage		$V_{GS}$	±20	V	
Continuous Drain Current <sup>G</sup>	T <sub>C</sub> =25°C		220	Α Α	
	T <sub>C</sub> =25°C	I <sub>D</sub>	205		
	T <sub>C</sub> =100°C		120		
Pulsed Drain Current <sup>C</sup>		I <sub>DM</sub>	772		
Continuous Drain Current	T <sub>A</sub> =25°C		44	Α	
	T <sub>A</sub> =70°C	IDSM	35		
Avalanche Current <sup>C</sup>		I <sub>AS</sub>	47	А	
Avalanche energy L=0.3mH <sup>C</sup>		E <sub>AS</sub>	331	mJ	
	T <sub>C</sub> =25°C	В	187	W	
Power Dissipation B	T <sub>C</sub> =100°C	P <sub>D</sub>	93		
	T <sub>A</sub> =25°C	В	8.3	10/	
Power Dissipation A T <sub>A</sub> =70°C		P <sub>DSM</sub>	5.3	W	
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 175	°C	

# Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units	
STATIC F	PARAMETERS						
$BV_{DSS}$	Drain-Source Breakdown Voltage	ID=250µA, VGS=0V		40			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =32V, V <sub>GS</sub> =0V				1	μA
	Zero Gate Voltage Drain Current					5	μΑ
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=250\mu A$		1.0	1.9	2.4	V
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS}$ =10V, $I_D$ =20A			2.5	2.8	mΩ
			T <sub>J</sub> =125°C		3.5	4.1	
		$V_{GS}$ =4.5V, $I_D$ =20A			3.45	4	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =5V, $I_D$ =20A			100		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V			0.7	1	V
Is	Maximum Body-Diode Continuous Curr	rent <sup>G</sup>			120	Α	
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance			5225		pF	
C <sub>oss</sub>	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =20V, f=1MHz			895		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			55		pF	
$R_g$	Gate resistance	f=1MHz		1	2	3.1	Ω
SWITCHI	NG PARAMETERS	•	•		•	•	•
Q <sub>g</sub> (10V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =20V, I <sub>D</sub> =20A			68	95	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge				28	40	nC
$Q_{gs}$	Gate Source Charge				16.5		nC
$Q_{gd}$	Gate Drain Charge				4.5		nC
Q <sub>oss</sub>	Output Charge	V <sub>GS</sub> =0V, V <sub>DS</sub> =20V			37		nC
t <sub>D(on)</sub>	Turn-On DelayTime				12.5		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =20V, $R_L$ =1 $\Omega$ , $R_{GEN}$ =3 $\Omega$			9.5		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				57.5		ns
t <sub>f</sub>	Turn-Off Fall Time	1		10.5		ns	
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, di/dt=500A/μs			20		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, di/dt=500A/μs			60		nC

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#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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V<sub>GS</sub> (Volts) Figure 5: On-Resistance vs. Gate-Source Voltage 0.0

0.2

0.4

V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics

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0.6

0.8

1.0

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

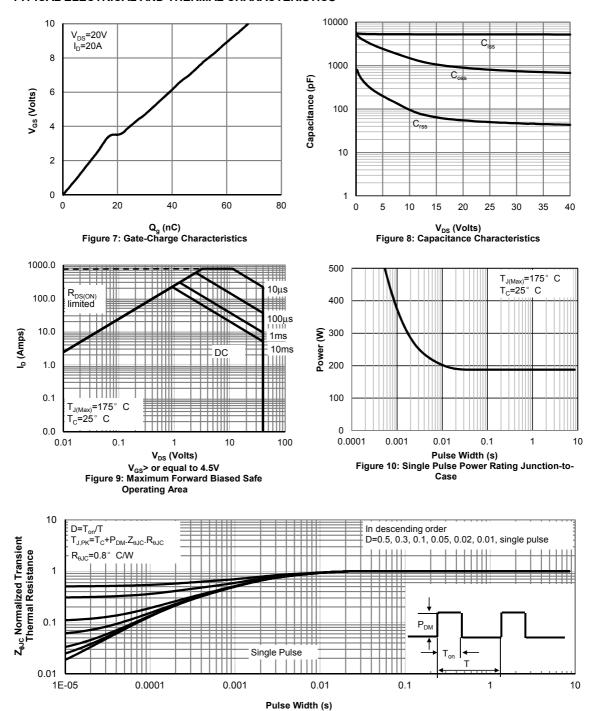
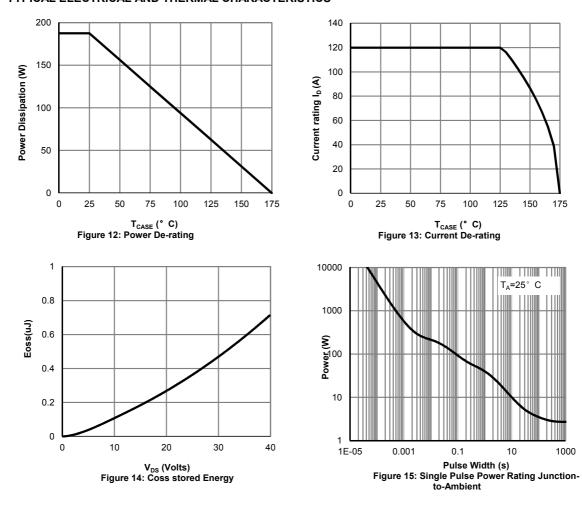
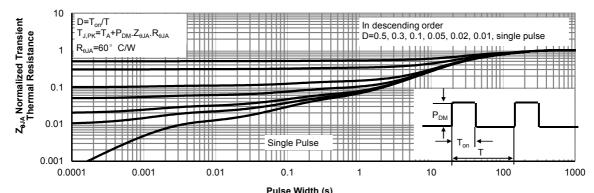


Figure 11: Normalized Maximum Transient Thermal Imp

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#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





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Pulse Width (s)
Figure 16: Normalized Maximum Transient Thermal Imp

Figure A: Gate Charge Test Circuit & Waveforms

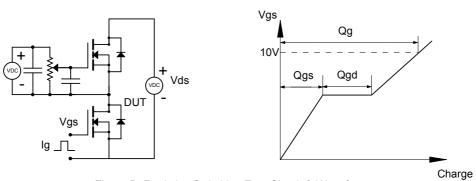


Figure B: Resistive Switching Test Circuit & Waveforms

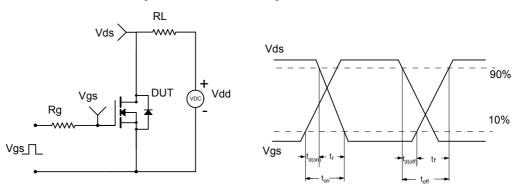


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

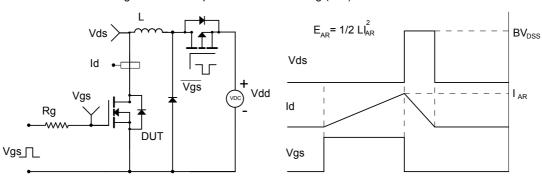
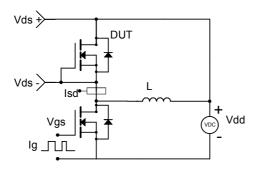
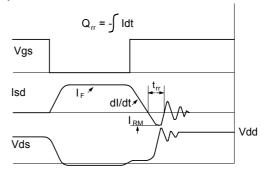


Figure D: Diode Recovery Test Circuit & Waveforms

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